



PATENT

-1-

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS
AND BARRIER LAYERS ON
PATTERNED WAFER WITH X-RAY
REFLECTOMETRY

Confirmation No.: 6057

Group No.: 2882

Examiner: H.K. Song

SMALL ENTITY STATEMENT
37 CFR 1.27

121 Spear Street, Suite 290
San Francisco, CA 94105

M/S ISSUE FEE

Commissioner for Patents

P.O. Box 1450

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CERTIFICATE OF MAILING

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STALLMAN & POLLOCK LLP

Dated: 12/ 3 /2003

By:

Georgia K. Stith
Georgia K. Stith

Sir:

Applicant is a small entity.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Date: December 3, 2003

By:

Michael A. Stallman
Michael A. Stallman (Reg. No. 29,444)

Attorneys for Applicant(s)

121 Spear Street, Suite 290
San Francisco, CA 94105
Tel.: (415) 512-1312
Fax: (415) 512-1362

Atty Docket No.: TWI-10820